



## Product Change Notification - JAON-13NOYH101

**Date:**

13 Mar 2018

**Product Category:**

Capacitive Touch Sensors; 8-bit PIC Microcontrollers

**Notification subject:**

CCB 2965.001 Final Notice: Qualification of MTAI as a new assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package using CuPdAu bond wire.

**Notification text:****PCN Status:**

Final notification

**PCN Type:**

Manufacturing Change

**Microchip Parts Affected:**

Please open the attachments found in the attachments field below labeled as PCN\_#\_Affected\_CPN.

NOTE: For your convenience Microchip includes identical files in two formats (.pdf and .xls).

**Description of Change:**

Qualification of MTAI as a new assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package using palladium coated copper wire with gold flash (CuPdAu) bond wire.

**Pre Change:**

Assembled at ANAC Assembly site with punched as a singulation method, using palladium coated copper wire (PdCu) bond wire and 8290 die attach material.

**Post Change:**

Assembled at MTAI Assembly site with sawn as a singulation method, using palladium coated copper wire with gold flash (CuPdAu) bond wire and 3280 die attach material.

**Pre and Post Change Summary:**

|                                  | Pre Change                                       | Post Change                               |
|----------------------------------|--|---|
| <b>Assembly Site</b>             | Amkor Assembly & Test (Shanghai) Co., LTD (ANAC) | Microchip Technology Thailand – HQ (MTAI) |
| <b>Wire material</b>             | PdCu   | CuPdAu                                    |
| <b>Die attach material</b>       | 8290   | 3280                                      |
| <b>Molding compound material</b> | G700   | G700                                      |
| <b>Lead frame material</b>       | C194   | C194                                      |
| <b>Singulation method</b>        | Punched  | Sawn                                      |

**Impacts to Data Sheet:**

None

**Change Impact:**

None

**Reason for Change:**

To improve productivity by qualifying MTAI assembly site with sawn as a singulation method and using palladium coated copper wire with gold flash (CuPdAu) bond wire

**Change Implementation Status:**

In Progress

**Estimated First Ship Date:**



April 13, 2018 (date code: 1815)

NOTE: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

**Time Table Summary:**

| Workweek                      | March 2018 |    |    |    |    | April 2018 |    |    |    |
|-------------------------------|------------|----|----|----|----|------------|----|----|----|
|                               | 09         | 10 | 11 | 12 | 13 | 14         | 15 | 16 | 17 |
| Qual Report Availability      |            |    | X  |    |    |            |    |    |    |
| Final PCN Issue Date          |            |    | X  |    |    |            |    |    |    |
| Estimated Implementation Date |            |    |    |    |    |            | X  |    |    |

**Method to Identify Change:**

Traceability code

**Qualification Report:**

Please open the attachments included with this PCN labeled as PCN\_#\_Qual Report.

**Revision History:**

**March 13, 2018:** Issued final notification. This PCN is qualified by similarity (QBS) to PCN # [KSRA-14SZTT575](#).

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

**Attachment(s):**

- [PCN\\_JAON-13NOYH101\\_Qual\\_Report.pdf](#)
- [PCN\\_JAON-13NOYH101\\_Affected\\_CPN.pdf](#)
- [PCN\\_JAON-13NOYH101\\_Affected\\_CPN.xlsx](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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To opt out of future offer or information emails (other than product change notification emails), click here to go to [microchipDIRECT](#) and login, then click on the "My account" link, click on "Update profile" and un-check the box that states "Future offers or information about Microchip's products or services."



**MICROCHIP**

**QUALIFICATION REPORT SUMMARY**  
RELIABILITY LABORATORY

**PCN#: JAON-13NOYH101**

**Date**  
**September 14, 2017**

**Qualification of MTAI as a new assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package using palladium coated copper wire with gold flash (CuPdAu) bond wire.**



## MICROCHIP PACKAGE QUALIFICATION REPORT

**Purpose :** Qualification of MTAI as a new assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package using palladium coated copper wire with gold flash (CuPdAu) bond wire.

**CCB No.:** 2965 and 2965.001

|                   |                               |   |
|-------------------|-------------------------------|---|
| <b>Misc.</b>      | <b>Assembly site</b>          | MTAI  |
|                   | <b>BD Number</b>              | BDM-001384 rev.A                                |
|                   | <b>MP Code (MPC)</b>          | 354T4QRXBA01                                    |
|                   | <b>Part Number (CPN)</b>      | AT90PWM81                                       |
| <b>Lead-Frame</b> | <b>Paddle size</b>            | 150x150 mils                                    |
|                   | <b>Material</b>               | C194  |
|                   | <b>Surface</b>                | Bare Cu on paddle                               |
|                   | <b>Treatment</b>              | BOT   |
|                   | <b>Process</b>                | Etched  |
|                   | <b>Lead-lock</b>              | Yes   |
|                   | <b>Part Number</b>            | 10103202  |
|                   | <b>Lead Plating</b>           | Matte Tin                                       |
|                   | <b>LF Matrix (RowxColumn)</b> | (11 row x 8 column x 5 panel)<br>440 pads/strip |
|                   | <b>Strip test capable</b>     | Yes   |
| <b>Bond Wire</b>  | <b>Material</b>               | CuPdAu  |
| <b>Die Attach</b> | <b>Part Number</b>            | 3280  |
|                   | <b>Conductive</b>             | Yes   |
| <b>MC</b>         | <b>Part Number</b>            | G700LTD   |
| <b>PKG</b>        | <b>PKG Type</b>               | VQFN  |
|                   | <b>Pin/Ball Count</b>         | 32  |
|                   | <b>PKG width/size</b>         | 5x5 mm  |
| <b>Die</b>        | <b>Die Thickness</b>          | 11 mils   |
|                   | <b>Die Size</b>               | 98.4x105.7 mils                                 |



# MICROCHIP PACKAGE QUALIFICATION REPORT

## Manufacturing Information

| Assembly Lot No.  | Wafer Lot No.     | Date Code |
|-------------------|-------------------|-----------|
| MTAI180903764.000 | MCSO518090268.000 | 1721H60   |
| MTAI180903765.000 | MCSO518090268.200 | 1721H62   |

## Result

Pass  Fail  \_\_\_\_\_

32L VQFN 5x5 assembled by MTAI pass reliability test per QCI-39000 which was conducted at MPHL rel lab. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

Note: Saw Isolation and singulation were performed at MPHIL.

# PACKAGE QUALIFICATION REPORT

| Test Number<br>(Reference)  | Test Condition  | Standard/<br>Method  | Qty.<br>(Acc.) | Def/SS | Result | Remarks                                 |
|---|---|----------------------|----------------|--------|--------|---|
| <u>Precondition</u><br><u>Prior Perform</u><br><u>Reliability Tests</u><br>(At MSL Level 1) | <b>Electrical Test</b> :+110°C, -40°C<br>System: MT9510 Handler 2580                            | JESD22-A113          | 900(0)         | 900    | Passed | Good Devices                            |
|   | Bake 150°C, 24 hrs<br>System: HERAEUS   |                      |                | 900    |        |   |
|   | 85°C/85%RH Moisture Soak 168 hrs.<br>System: Climats Excal 5423-HE                              | IPC/JEDEC J-STD-020D |                | 900    |        |   |
|   | 3x Convection-Reflow 265°C max<br>System: Mancorp CR.5000F                                      |                      |                | 900    |        |   |
|   | <b>Electrical Test</b> :+110°C, -40°C<br>System: MT9510 Handler 2580                            |                      |                | 0/900  | Passed |   |
| <b>Temp Cycle</b>   | <b>Stress Condition:</b> (Standard)<br>65°C to +150°C, 500 Cycles<br>System : VOTSCH VT 7012 S2 | JESD22-A104          |                | 249    |        | Parts had been pre-conditioned at 260°C |
|   | <b>Electrical Test:</b> +110°C, -40°C<br>System: MT9510 Handler:2580                            |                      | 249(0)         | 0/249  | Passed |   |
|   | <b>Bond Strength:</b><br>Wire Pull (> 2.50 grams)<br>Bond Shear (>15.00 grams)                  |                      | 15(0)          |        | Passed |   |

# PACKAGE QUALIFICATION REPORT

| Test Number (Reference)              | Test Condition  | Standard/ Method       | Qty. (Acc.)  | Def/SS. | Result | Remarks                                 |
|--------------------------------------|---|------------------------|--------------|---------|--------|---|
| <b>UNBIASED-HAST</b>                 | <b>Stress Condition:</b> (Standard)<br>+130°C/85%RH, 96 hrs.<br>System: HIRAYAMA HASTEST PC-422R8   | JESD22-A118            |              | 240     |        | Parts had been pre-conditioned at 260°C |
|                                      | <b>Electrical Test:</b> +110°C, -40°C<br>System: MT9510 Handler:2580  |                        | 240          | 0/240   | Passed |   |
| <b>HAST</b>                          | <b>Stress Condition:</b> (Standard)<br>+130°C/85%RH, 96 hrs. <b>Bias Volt:</b> 5.5 Volts<br>System: HIRAYAMA HASTEST PC-422R8                       | JESD22-A110            |              | 246     |        | Parts had been pre-conditioned at 260°C |
|                                      | <b>Electrical Test:</b> +110°C, -40°C<br>System: MT9510 Handler:2580  |                        | 246          | 0/246   | Passed |   |
| <b>High Temperature Storage Life</b> | <b>Stress Condition:</b><br>Bake 175°C, 504 hrs<br>System: HERAEUS  | JESD22-A103            |              | 50      |        | 50 units                                |
|                                      | <b>Electrical Test</b> :+110°C, -40°C<br>System: MT9510 Handler:2580  |                        | 45(0)        | 0/50    | Pass   |   |
| <b>Solderability Temp 245°C</b>      | <b>Bake:</b> Temp 155°C,4Hrs<br>System: Oven<br>Solder Bath: Temp.245°C<br>Solder material: SAC305<br>Visual Inspection: External Visual Inspection | JESD22B-102E           | 15 (0)       | 0/15    | Pass   | Performed at MPHIL                      |
| <b>Physical Dimensions</b>           | Physical Dimension,<br>30 units from 1 lot  | JESD22-B100/B108       | 30(0) Units  | 0/30    | Pass   | Performed at MPHIL                      |
| <b>Bond Strength Data Assembly</b>   | Wire Pull (> 2.50 grams)  | M2011.8<br>MIL-STD-883 | 30 (0) Wires |         | Pass   |   |
|                                      | Bond Shear (>15.00 grams)   | M2011.8<br>MIL-STD-883 | 30 (0) bonds |         | Pass   |   |

# PACKAGE QUALIFICATION REPORT

| Test Number<br>(Reference)           | Test Condition  | Standard/<br>Method    | Qty.<br>(Acc.) | Def/SS. | Result | Remarks            |
|--------------------------------------|---|------------------------|----------------|---------|--------|--------------------|
| <b>High Temperature Storage Life</b> | <b>Stress Condition:</b><br>Bake 175°C, 504 hrs<br>System: HERAEUS  | JESD22-A103            |                | 50      |        | 50 units           |
|                                      | <b>Electrical Test</b> :+110°C, -40°C<br>System: MT9510 Handler:2580  |                        | 45(0)          | 0/50    | Pass   |                    |
| <b>Solderability Temp 245°C</b>      | <b>Bake:</b> Temp 155°C,4Hrs<br>System: Oven<br>Solder Bath: Temp.245°C<br>Solder material: SAC305<br>Visual Inspection: External Visual Inspection | JESD22B-102E           | 15 (0)         | 0/15    | Pass   | Performed at MPHIL |
| <b>Physical Dimensions</b>           | Physical Dimension,<br>30 units from 1 lot  | JESD22-B100/B108       | 30(0) Units    | 0/30    | Pass   | Performed at MPHIL |
| <b>Bond Strength Data Assembly</b>   | Wire Pull (> 2.50 grams)  | M2011.8<br>MIL-STD-883 | 30 (0) Wires   |         | Pass   |                    |
|                                      | Bond Shear (>15.00 grams)   | M2011.8<br>MIL-STD-883 | 30 (0) bonds   |         | Pass   |                    |



JAON-13NOYH101 - CCB 2965.001 Final Notice: Qualification of MTAI as an additional assembly site for selected Atmel products available in 32L VQFN (5x5x0.9mm) package using CuPdAu bond wire.

Affected Catalog Part Numbers (CPN)

| PCN_JAON-13NOYH101 |
|--------------------|
| CATALOG_PART_NBR   |
| AT42QT1110-MUR     |
| AT42QT11C12-MUR    |
| AT42QT1244-MU      |
| AT42QT2100-MUR     |
| ATMEGA168A-MU      |
| ATMEGA168A-MUR     |
| ATMEGA168PA-MN     |
| ATMEGA168PA-MNR    |
| ATMEGA168PA-MU     |
| ATMEGA168PA-MUR    |
| ATMEGA168PA-MUR431 |
| ATMEGA48-20MU      |
| ATMEGA48-20MUR     |
| ATMEGA48A-MU       |
| ATMEGA48A-MUR      |
| ATMEGA48P-20MU     |
| ATMEGA48P-20MUR    |
| ATMEGA48PA-MN      |
| ATMEGA48PA-MNR     |
| ATMEGA48PA-MU      |
| ATMEGA48PA-MUR     |
| ATMEGA48PV-10MU    |
| ATMEGA48PV-10MUR   |
| ATMEGA48V-10MU     |
| ATMEGA48V-10MUR    |
| ATMEGA48V-10MUR173 |
| ATMEGA48V-10MUR348 |
| ATMEGA8-16MU       |
| ATMEGA8-16MUR      |
| ATMEGA88-20MU      |
| ATMEGA88-20MUR     |
| ATMEGA88-20MURA4   |
| ATMEGA88A-MU       |
| ATMEGA88A-MUR      |
| ATMEGA88P-20MU     |
| ATMEGA88P-20MUR    |
| ATMEGA88PA-MN      |
| ATMEGA88PA-MNR     |
| ATMEGA88PA-MU      |
| ATMEGA88PA-MUR     |
| ATMEGA88PA-MURA06  |
| ATMEGA88PA-MURA6   |
| ATMEGA88PV-10MU    |

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Affected Catalog Part Numbers (CPN)

| PCN_JAON-13NOYH101 |
|--------------------|
| CATALOG_PART_NBR   |
| ATMEGA88PV-10MUR   |
| ATMEGA88V-10MU     |
| ATMEGA88V-10MUR    |
| ATMEGA88V-10MUR360 |
| ATMEGA88V-10MUR378 |
| ATMEGA88V-10MUR379 |
| ATMEGA8A-MN        |
| ATMEGA8A-MNR       |
| ATMEGA8A-MU        |
| ATMEGA8A-MUR       |
| ATMEGA8A-MURA7     |
| ATMEGA8L-8MU       |
| ATMEGA8L-8MUA4     |
| ATMEGA8L-8MUR      |
| ATMEGA8L-8MURA3    |
| ATTINY26-16MU      |
| ATTINY26-16MUR     |
| ATTINY261A-MFRA0   |
| ATTINY261A-MN      |
| ATTINY261A-MNR     |
| ATTINY261A-MU      |
| ATTINY261A-MUR     |
| ATTINY26L-8MU      |
| ATTINY26L-8MUR     |
| ATTINY28L-4MU      |
| ATTINY28L-4MUR     |
| ATTINY28V-1MU      |
| ATTINY28V-1MUR     |
| ATTINY461-20MU     |
| ATTINY461-20MUR    |
| ATTINY461-20MUR553 |
| ATTINY461A-MU      |
| ATTINY461A-MUR     |
| ATTINY461V-10MU    |
| ATTINY461V-10MUR   |
| ATTINY48-MU        |
| ATTINY48-MUR       |
| ATTINY48-MUR522    |
| ATTINY48-MUR547    |
| ATTINY861-20MU     |
| ATTINY861-20MUR    |
| ATTINY861-20MUR430 |
| ATTINY861A-MU      |

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Affected Catalog Part Numbers (CPN)

| PCN_JAON-13NOYH101 |
|--------------------|
| CATALOG_PART_NBR   |
| ATTINY861A-MUR     |
| ATTINY861V-10MU    |
| ATTINY861V-10MUR   |
| ATTINY88-MU        |
| ATTINY88-MUR       |